

Search Notes

Application/Control No.

10/721,334

Examiner

HIEU T. VO

Applicant(s)/Patent under
Reexamination

KOBAYASHI ET AL.

Art Unit

3747

SEARCHED

Class	Subclass	Date	Examiner
701	114 115 101 102 29 35	6/23/2005	VH
73	116 117.3	6/23/2005	VH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/27/2005	VH